Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination	_
10/009,579	DE LEIJ ET AL.	
Examiner	Art Unit	_
Celine X Oian Ph D	1636	

	SEARCHED			
Class	Subclass	Date	Examiner	
			,	
	<u>.</u>			

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
L			

SEARCH I (INCLUDING SEAR	NOTES CH STRATEGY	
	DATE	EXMR
updated: see attached	5/10/2006	CQ
····		